

<b>Notice of References Cited</b>	Application/Control No. 10/557,745		Applicant(s)/Patent Under Reexamination HAYASHI, FUMIHIRO	
	Examiner Hai Vo		Art Unit 1794	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0034373	02-2004	Schuldt-Hempe et al.	606/151
*	B	US-2003/0187516	10-2003	Amid et al.	623/23.72
*	C	US-6,546,292	04-2003	Steinhaus et al.	607/116
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
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	K	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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